FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 025720-00020

SERIAL NO. 10/724,577

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

Michio MIURA et al.

FILING DATE

APPLICANT

GROUP 2817

December 1, 2003

U.S. PATENT DOCUMENTS

					, 		
EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
	AA						
	АВ		· · · · · · · · · · · · · · · · · · ·				
	AC						
	AD						
	AE						
	AF						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB- CLASS	TR/ YES	NSLAT	TION PART.
38	AG	2516817	April 30, 1996	Japan	-41	22			х
150	АН	11-55070	February 26, 1999	Japan	-9	-25-	х		
BS	Al	9-208399	August 12, 1997	Japan	-33	-08			Х
	AJ		<u> </u>						
	AK								
	AL								

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

BS AM	SAW Properties of SiO2/128° Y-X LiNbO3 Structure Fabricated by Magnetron Sputtering Technique Kazuhiki YAMANOUCHI, Member IEEE, and Satoshi HAYAMA, IEEE Transactions on Sonics And Litrasonics, Vol. Su-31, No. 1, January 1984, pp. 51-57.
B8 AN	Temperature Stable SAW Devices Using Directly Bonded LiTa03/Glass Substrates H. SATO, K. ONISHI, T. SHIMAMURA, and Y. TOMITA, 1998 IEEE LITTASONICS Symposium, Vol. 1, October 1998, pp. 335-338,
BS AO	Theoretical Analysis of SAW Propagation Characteristics under the Strained Medium and Applications for High Temperature Stable High Coupling SAW Substrates K. YAMANOUCHI, K. KOTANI, H. ODAGAWA, and Y. CHO. 1999 IEEE Ultrasonics Symposium.

EXAMINER Boul	aia Summons
(30000	July 1

DATE CONSIDERED

2/15/05

*EXAMINER:

Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.